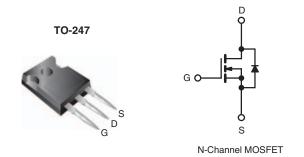


COMPLIANT

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	800	800		
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	1.2		
Q _g (Max.) (nC)	200	0		
Q _{gs} (nC)	24			
Q _{gd} (nC)	110	110		
Configuration	Sing	Single		



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRFPE50PbF
Leau (FD)-liee	SiHFPE50-E3
SnPb	IRFPE50
SIIFD	SiHFPE50

ABSOLUTE MAXIMUM RATINGS T	C = 25 °C, unless otherw	rise noted			
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V_{DS}	800	V	
Gate-Source Voltage		V_{GS}	± 20		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 ^{\circ}C$	I _D	7.8		
	T _C =100°C		4.9	Α	
Pulsed Drain Current ^a	I _{DM}	31			
Linear Derating Factor			1.5	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	770	mJ	
Repetitive Avalanche Current ^a		I _{AR}	7.8	А	
Repetitive Avalanche Energy ^a		E _{AR}	19	mJ	
Maximum Power Dissipation	T _C = 25 °C	P _D	190	W	
Peak Diode Recovery dV/dt ^c		dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s	-	300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	6-32 OF IVIS SCIEW		1.1	N · m	

Notes

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- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 23 \,\text{mH}$, $R_G = 25 \,\Omega$, $I_{AS} = 7.8 \,\text{A}$ (see fig. 12).
- c. $I_{SD} \le 7.8 \text{ A}$, $dI/dt \le 140 \text{ A/}\mu\text{s}$, $V_{DD} \le 600 \text{ V}$, $T_J \le 150 \,^{\circ}\text{C}$.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	40	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65	

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	ı
Static				ı			
Drain-Source Breakdown Voltage	V_{DS}	V _{GS}	= 0 V, I _D = 250 μA	800	-	-	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA	-	0.98	-	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$		-	-	100 500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 4.7 A ^b	-	-	1.2	
Forward Transconductance	9fs		= 100 V, I _D = 4.7 A ^b	5.6	-	-	
Dynamic	_	1		l			<u> </u>
Input Capacitance	C _{iss}	V 0V		-	3100	-	pF
Output Capacitance	C _{oss}		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		800	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	490	-	
Total Gate Charge	Q_{g}		-	-	200	nC	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 7.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b		-	-		24
Gate-Drain Charge	Q _{gd}			-	-		110
Turn-On Delay Time	t _{d(on)}			-	19	-	
Rise Time	t _r	V _{DD} =	= 400 V, I _D = 7.8 A,	-	38	-	ns
Turn-Off Delay Time	t _{d(off)}	R _G =	= 6.2 Ω , R _D = 52 Ω	-	120	-	
Fall Time	t _f	see fig. 10 ^b		-	39	-	1
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	
Internal Source Inductance	L _S			-	13	-	- n⊦
Drain-Source Body Diode Characteristic	cs					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7.8	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	31	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 7.8 A, V _{GS} = 0 V ^b		-	-	1.8	
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 7.8 A, dl/dt = 100 A/μs ^b		-	650	980	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn		on ic dor	ningted b	vl ond	-

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

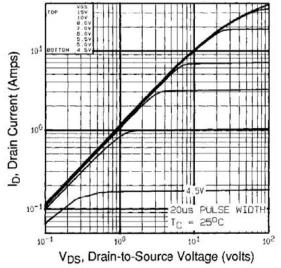
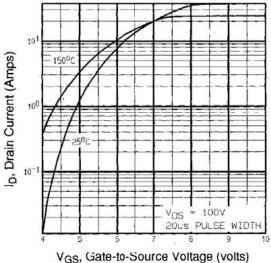


Fig. 1 - Typical Output Characteristics, T_C = 25 °C



V_{GS}, Gate-to-Source Voltage (volts) Fig. 3 - Typical Transfer Characteristics

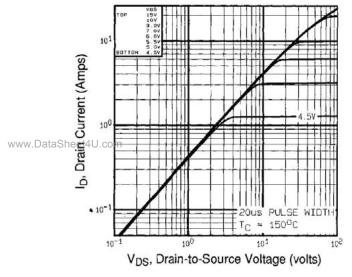


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

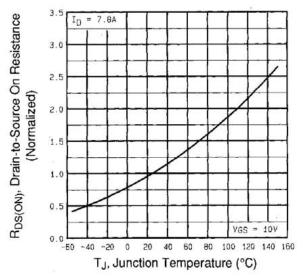


Fig. 4 - Normalized On-Resistance vs. Temperature



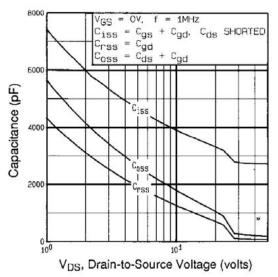


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

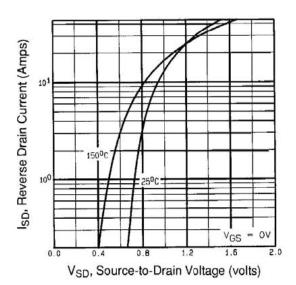


Fig. 7 - Typical Source-Drain Diode Forward Voltage

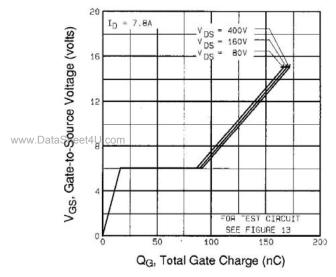


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

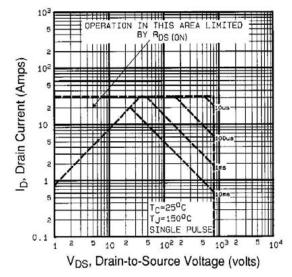


Fig. 8 - Maximum Safe Operating Area



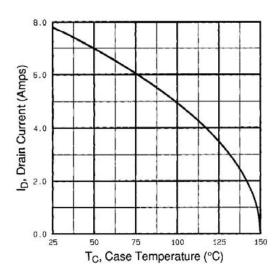


Fig. 9 - Maximum Drain Current vs. Case Temperature

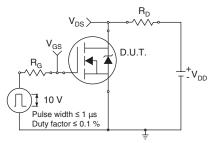


Fig. 10a - Switching Time Test Circuit

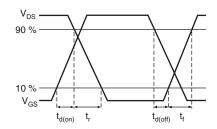


Fig. 10b - Switching Time Waveforms

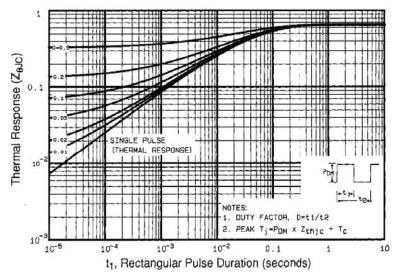


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

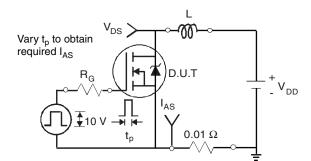


Fig. 12a - Unclamped Inductive Test Circuit

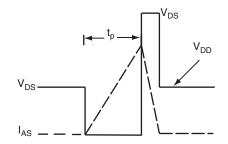


Fig. 12b - Unclamped Inductive Waveforms

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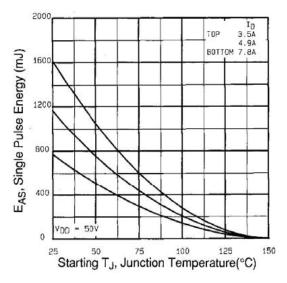


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

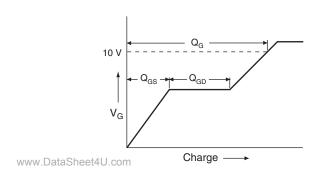


Fig. 13a - Basic Gate Charge Waveform

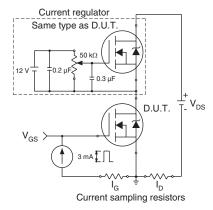
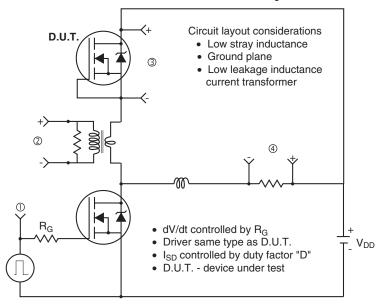
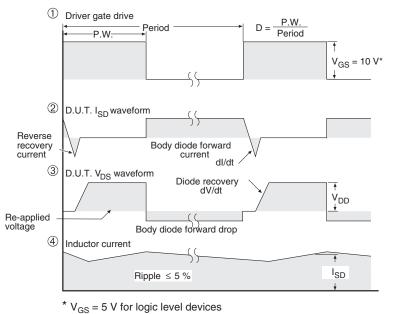


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





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VGS = 0 V for logic lover devices

Fig. 14 - For N-Channel

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